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June 2014

# **FDMC7692S**

# N-Channel PowerTrench<sup>®</sup> SyncFET<sup>TM</sup> 30 V, 18 A, 9.3 m $\Omega$

#### **Features**

- Max  $r_{DS(on)} = 9.3 \text{ m}\Omega$  at  $V_{GS} = 10 \text{ V}$ ,  $I_D = 12.5 \text{ A}$
- Max  $r_{DS(on)}$  = 13.6 m $\Omega$  at  $V_{GS}$  = 4.5 V,  $I_D$  = 10.4 A
- High performance technology for extremely low r<sub>DS(on)</sub>
- Termination is Lead-free and RoHS Compliant

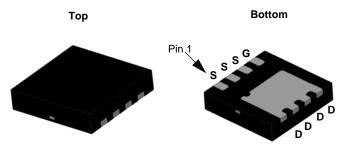
## **General Description**

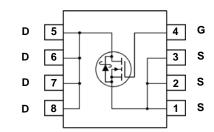
This FDMC7692S is produced using Fairchild Semiconductor's advanced PowerTrench® process that has been especially tailored to minimize the on-state resistance. This device is well suited for Power Management and load switching applications common in Notebook Computers and Portable Battery packs.

# **Applications**

- DC DC Buck Converters
- Notebook DC DC application







MLP 3.3x3.3

# MOSFET Maximum Ratings T<sub>A</sub> = 25 °C unless otherwise noted

Symbol	Param	eter		Ratings	Units
$V_{DS}$	Drain to Source Voltage			30	V
$V_{GS}$	Gate to Source Voltage			±20	V
I <sub>D</sub>	Drain Current -Continuous	T <sub>C</sub> = 25 °C		18	
	-Continuous	T <sub>A</sub> = 25 °C	(Note 1a)	12.5	Α
	-Pulsed			45	
E <sub>AS</sub>	Sinlge Pulse Avalanche Energy		(Note 3)	21	mJ
P <sub>D</sub>	Power Dissipation	T <sub>C</sub> = 25 °C		27	W
	Power Dissipation	T <sub>A</sub> = 25 °C	(Note 1a)	2.3	VV
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Tempera	ature Range		-55 to +150	°C

#### **Thermal Characteristics**

$R_{\theta JC}$	Thermal Resistance, Junction to Case		4.7	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	53	°C/W

### **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMC7692S	FDMC7692S	MLP 3.3X3.3	13 "	12 mm	3000 units

# **Electrical Characteristics** T<sub>J</sub> = 25 °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	cteristics					
$BV_{DSS}$	Drain to Source Breakdown Voltage	$I_D = 1 \text{ mA}, V_{GS} = 0 \text{ V}$	30			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 10 mA, referenced to 25 °C		16		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 24 V, V <sub>GS</sub> = 0 V			500	μΑ
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$			100	nA

#### On Characteristics (Note 2)

V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}$ , $I_D = 1 \text{ mA}$	1.2	2.0	3.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I <sub>D</sub> = 10 mA, referenced to 25 °C		-5		mV/°C
r <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = 10 \text{ V}, I_D = 12.5 \text{ A}$		7.8	9.3	mΩ
		$V_{GS} = 4.5 \text{ V}, I_D = 10.4 \text{ A}$		10.8	13.6	
		$V_{GS} = 10 \text{ V}, I_D = 12.5 \text{ A}$ $T_J = 125 ^{\circ}\text{C}$		9.6	13.0	
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = 5 \text{ V}, I_{D} = 12.5 \text{ A}$		62		S

#### **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V 45.V.V 0.V	1040	1385	pF
Coss	Output Capacitance	V <sub>DS</sub> = 15 V, V <sub>GS</sub> = 0 V, f = 1 MHz	445	590	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 = 1 1011 12	40	60	pF
$R_{q}$	Gate Resistance		1.1	2.9	Ω

#### **Switching Characteristics**

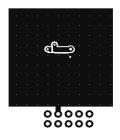
t <sub>d(on)</sub>	Turn-On Delay Time		9	17	ns
t <sub>r</sub>	Rise Time	V <sub>DD</sub> = 15 V, I <sub>D</sub> = 12.5 A,	3	10	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS} = 10 \text{ V}, R_{GEN} = 6 \Omega$	19	34	ns
t <sub>f</sub>	Fall Time		3	10	ns
Qg	Total Gate Charge	V <sub>GS</sub> = 0 V to 10 V	16	23	nC
Qg	Total Gate Charge	$V_{GS} = 0 \text{ V to } 4.5 \text{ V}$ $V_{DD} = 15 \text{ V}$	8	10	nC
$Q_{gs}$	Gate to Source Gate Charge	I <sub>D</sub> = 12.5 A	4		nC
Q <sub>ad</sub>	Gate to Drain "Miller" Charge		2		nC

#### **Drain-Source Diode Characteristics**

V <sub>SD</sub>	Source to Drain Dioge Forward voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 12.5 A (Note 2)	0.9	1.3	V
		$V_{GS} = 0 \text{ V}, I_{S} = 0.9 \text{ A}$ (Note 2)	0.5	0.7	, v
t <sub>rr</sub>	Reverse Recovery Time	I <sub>E</sub> = 12.5 A, di/dt = 300 A/μs	21	33	ns
Q <sub>rr</sub>	Reverse Recovery Charge	T <sub>F</sub> = 12.5 A, α//αt = 300 A/μs	16	29	nC

Notes

<sup>1.</sup> R<sub>θJA</sub> is determined with the device mounted on a 1in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R<sub>θJC</sub> is guaranteed by design while R<sub>θCA</sub> is determined by the user's board design.



a. 53 °C/W when mounted on a 1 in² pad of 2 oz copper.



b. 125 °C/W when mounted on a minimum pad of 2 oz copper.

<sup>2.</sup> Pulse Test: Pulse Width < 300  $\mu$ s, Duty cycle < 2.0%.

<sup>3.</sup>  $E_{AS}$  of 21 mJ is based on starting  $T_J$  = 25 °C, L = 0.3 mH,  $I_{AS}$  = 12.0 A,  $V_{DD}$  = 27 V,  $V_{GS}$  = 10 V. 100% test at L = 3 mH,  $I_{AS}$  = 3.2 A .

# Typical Characteristics T<sub>J</sub> = 25 °C unless otherwise noted

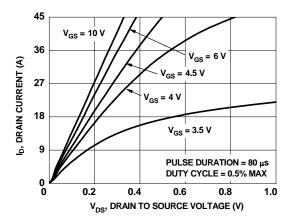


Figure 1. On-Region Characteristics

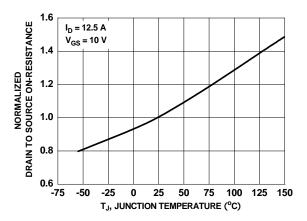


Figure 3. Normalized On-Resistance vs Junction Temperature

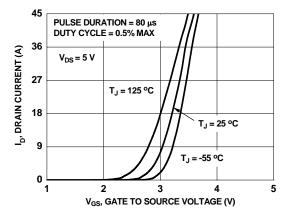


Figure 5. Transfer Characteristics

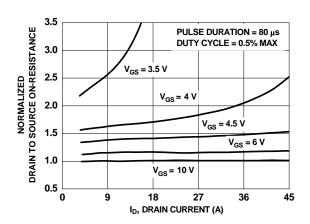


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

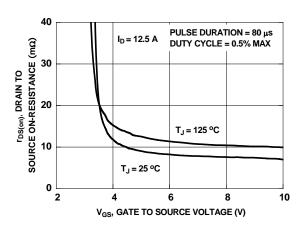


Figure 4. On-Resistance vs Gate to Source Voltage

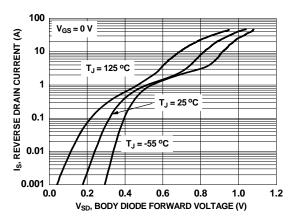


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

# **Typical Characteristics** $T_J = 25$ °C unless otherwise noted

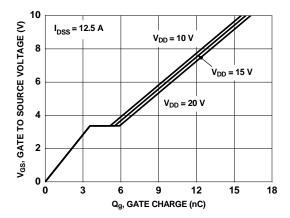


Figure 7. Gate Charge Characteristics

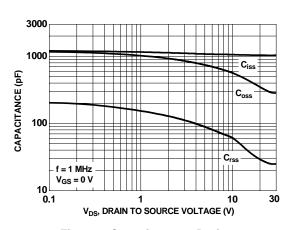


Figure 8. Capacitance vs Drain to Source Voltage

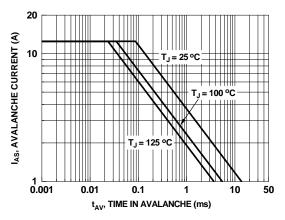


Figure 9. Unclamped Inductive Switching Capability

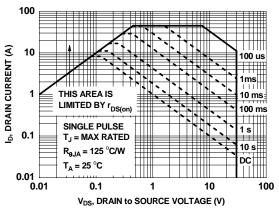


Figure 10. Forward Bias Safe Operating Area

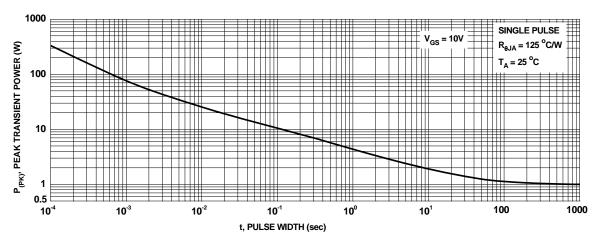


Figure 11. Single Pulse Maximum Power Dissipation

# **Typical Characteristics** T<sub>J</sub> = 25 °C unless otherwise noted

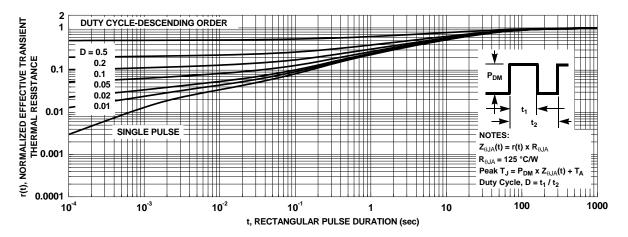


Figure 12. Junction-to-Ambient Transient Thermal Response Curve

# Typical Characteristics (continued)

# SyncFET Schottky body diode Characteristics

Fairchild's SyncFET process embeds a Schottky diode in parallel with PowerTrench MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 13 shows the reverse recovery characteristic of the FDMC7692S.

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

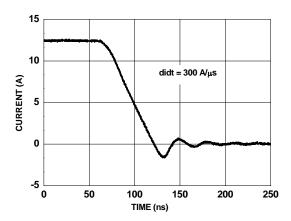


Figure 13. SyncFET body diode reverse recovery characteristic

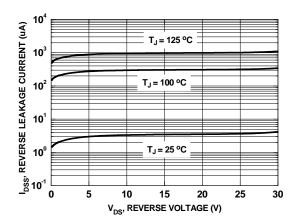
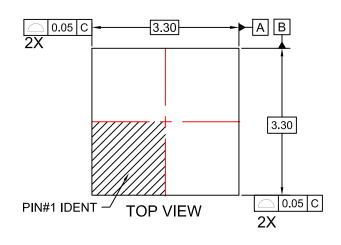
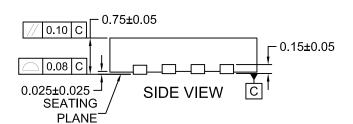
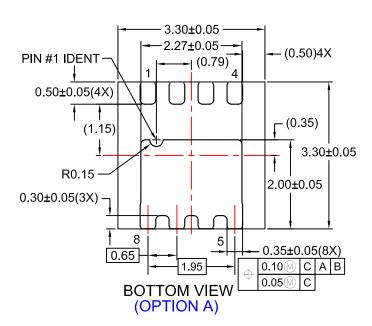
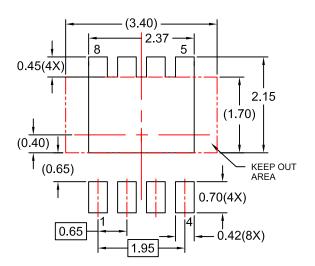


Figure 14. SyncFET body diode reverse leakage versus drain-source voltage

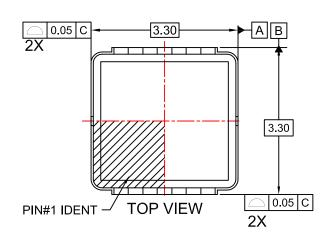


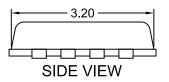


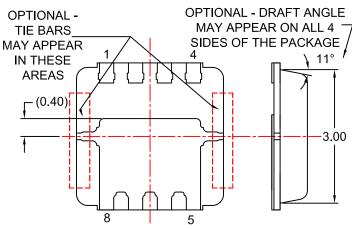






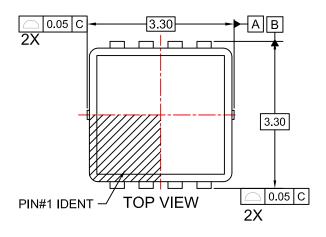


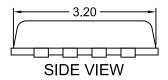


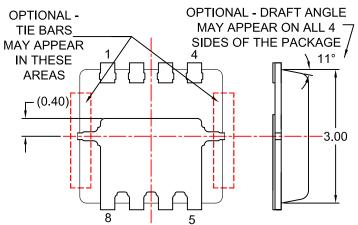


ALL DIMENSIONS AS PER OPTION A
UNLESS SPECIFIED
BOTTOM VIEW
(OPTION B)







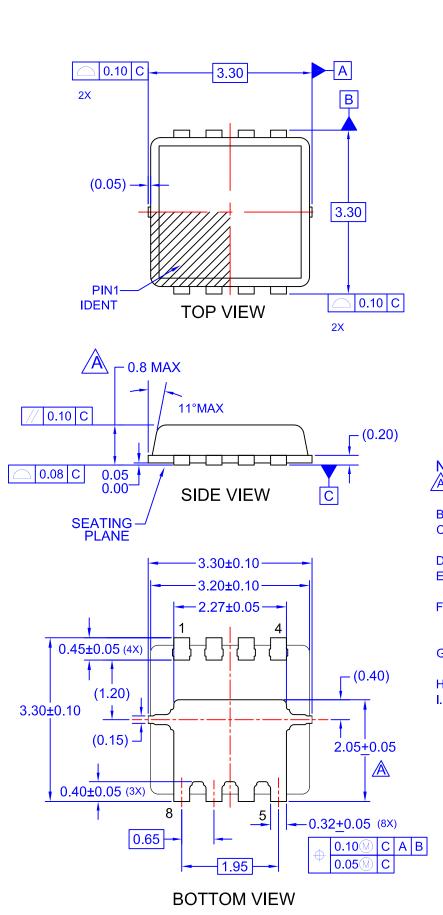


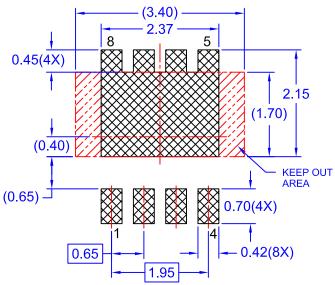
ALL DIMENSIONS AS PER OPTION A
UNLESS SPECIFIED
BOTTOM VIEW
(OPTION C)

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- A. PACKAGE DOES NOT FULLY CONFORM TO JEDEC REGISTRATION MO-240.
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 2009.
- D. LAND PATTERN RECOMMENDATION IS EXISTING INDUSTRY LAND PATTERN
- E. DIMENSIONS DO NOT INCLUDE BURRS OR MOLD FLASH. BURRS OR MOLD FLASH SHALL NOT EXCEED 0.10MM.
- F. DRAWING FILENAME: MKT-MLP08Wrev3.
- G. OPTION A SAWN MLP, OPTIONS B & C PUNCH MLP.





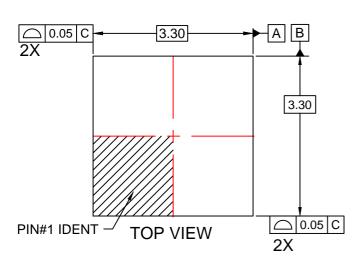


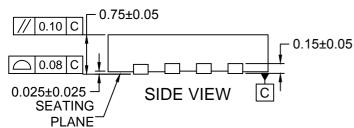
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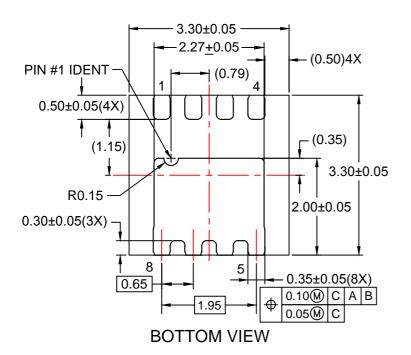
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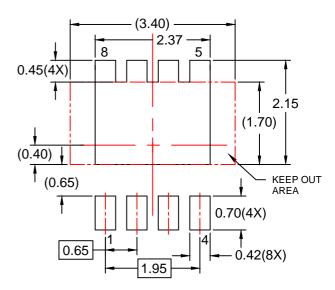
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